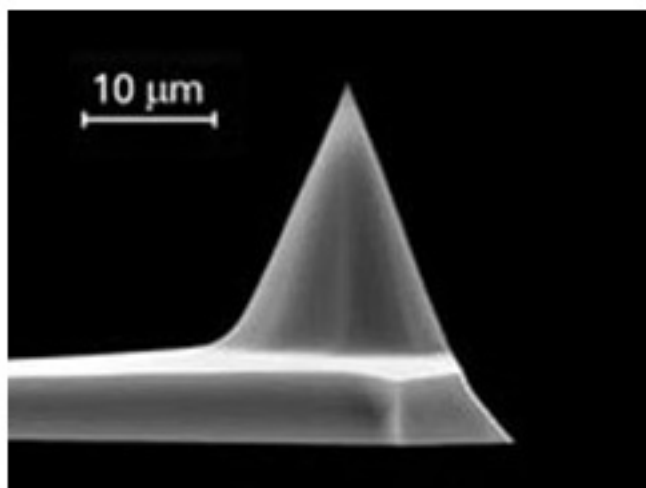


NSC15

PROBE



MikroMasch中国代理：
本原纳米仪器有限公司
Tel: 800-830-3560



SEM image of uncoated silicon SPM probe tip

Silicon etched probe tip of the NSC series has a conical shape.

Typical probe tip radius of uncoated tip
10 nm

Full tip cone angle*
40°

Tip aspect ratio
more than 3:1 (4:1 typical)

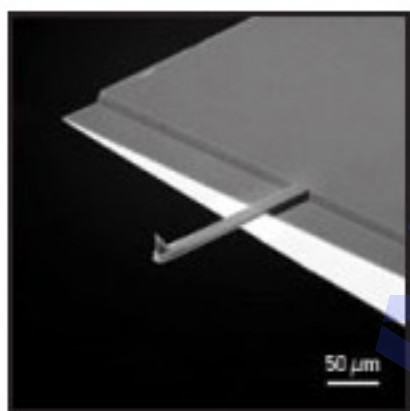
Total tip height
20..25 μm

Probe material
n-type silicon (phosphorus doped)

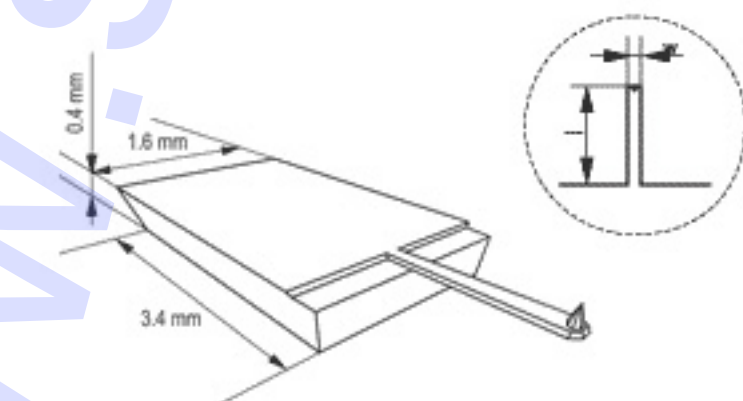
Probe bulk resistivity
0.01..0.05 Ohm*cm

*The full cone angle may be less than 40° at the last 200 nm of the tip end.

CANTILEVER



SEM image of Silicon cantilever and probe.



Schematic drawing of the probe chip.

Cantilever	Resonant Frequency, kHz			Spring Constant, N/m			Length l ± 5, μm	Width w ± 3, μm	Thickness t ± 0.5, μm
	min	typ	max	min	typ	max			
15 Series	265	325	400	20	40	75	125	35	4.0